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ON THE COVER: Nitrogen ion implantation is becoming widely used for treating titanium alloy knee joints. See "Ion Implantation" by S.T. Picraux and P.S. Percy in this issue. (Photo courtesy of Spire Corporation.)

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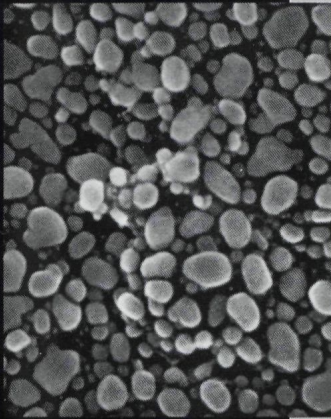
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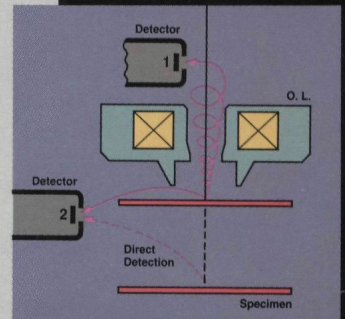
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